TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOS III)

TPCF8101

Notebook PC Applications Portable Equipment Applications

- Low drain-source ON resistance: RDS (ON) = 22 m Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 14 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = -10 \mu A \text{ (max) (V}_{DS} = -12 \text{ V)}$
- Enhancement model: $V_{th} = -0.5 \text{ to } -1.2 \text{ V}$

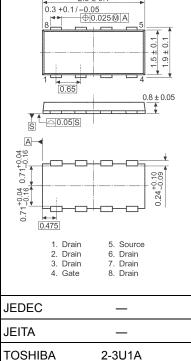
 $(V_{DS} = -10 \text{ V}, I_{D} = -200 \text{ }\mu\text{A})$

Absolute Maximum Ratings (Ta = 25°C)

Characte	ristics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	-12	V
Drain-gate voltage (R	_{GS} = 20 kΩ)	V_{DGR}	-12	V
Gate-source voltage		V _{GSS}	±8	V
Drain current	DC (Note 1)	ID	-6	^
Drain current	Pulsed (Note 1)	I _{DP}	-24	Α
Drain power dissipation	on (t = 5 s) (Note 2a)	P _D	2.5	W
Drain power dissipation	on (t = 5 s) (Note 2b)	P _D	0.7	W
Single pulse avalanch	ne energy (Note 3)	E _{AS}	6.3	mJ
Avalanche current		I _{AR}	-3	Α
Repetitive avalanche	energy (Note 4)	E _{AR}	0.25	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature	range	T _{stg}	-55~150	°C

 2.9 ± 0.1

Unit: mm



Weight: 0.011 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

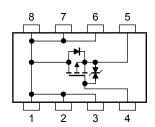
Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	R _{th (ch-a)}	50.0	°C/W
Thermal resistance, channel to ambient (t = 5 s) (Note 2b)	R _{th (ch-a)}	178.6	°C/W

Note: (Note 1), (Note 2), (Note 3), (Note 4) and (Note 5): See the next page.

This transistor is an electrostatic-sensitive device. Please handle with caution.

Circuit Configuration



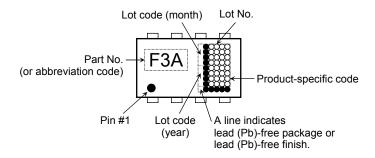
Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cui	te leakage current		$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ	
Drain cut-off curr	ent	I _{DSS}	$V_{DS} = -12 \text{ V}, V_{GS} = 0 \text{ V}$			-10	μА	
Drain-source breakdown voltage		V _{(BR) DSS}	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-12	_	_	· V	
		V _{(BR)DSX}	$I_D = -10$ mA, $V_{GS} = 8$ V	-4	_			
Gate threshold ve	oltage	V _{th}	$V_{DS} = -10 \text{ V}, I_D = -200 \mu\text{A}$	-0.5	_	-1.2	V	
		R _{DS} (ON)	$V_{GS} = -1.8 \text{ V}, I_D = -1.5 \text{ A}$	_	60	85		
Drain-source ON	resistance	R _{DS} (ON)	$V_{GS} = -2.5 \text{ V}, I_D = -3.0 \text{ A}$	_	32	40	mΩ	
		R _{DS} (ON)	$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$	_	22	28		
Forward transfer	admittance	Y _{fs}	$V_{DS} = -10 \text{ V}, I_D = -3.0 \text{ A}$	7	14	_	S	
Input capacitance		C _{iss}		_	1600	_	pF	
Reverse transfer capacitance		C _{rss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	260	_		
Output capacitance		Coss		_	335	_		
	Rise time	t _r	0 V 7 F I _D = -3.0 A	_	7	_		
Considerable and disease	Turn-on time	t _{on}	$V_{GS} = -3.0 \text{ A}$ $V_{GS} = -5 \text{ V}$ $C \neq C \neq$	_	13	_	-	
Switching time	Fall time	t _f	4.7 D	_	21	_	ns	
	Turn-off time	t _{off}	$V_{DD} \simeq -6 \text{ V}$ Duty \leq 1%, $t_W = 10 \mu\text{s}$	_	68	_		
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ -10 V, V _{GS} = -5 V,	_	18.0	_		
Gate-source charge		Q _{gs}	$I_D = -6.0 \text{ A}$	_	14.5	_	nC	
Gate-drain ("miller") charge		Q _{gd}		_	3.5	_		

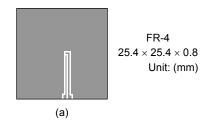
Source-Drain Ratings and Characteristics (Ta = 25°C)

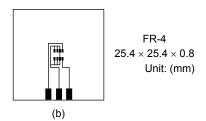
Characteristics Sym		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	-24	Α
Forward voltage	Forward voltage (diode) V _{DSF}		$I_{DR} = -6.0 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.2	V

Marking (Note 5)



- Note 1: Ensure that the channel temperature does not exceed 150°C.
- Note 2: (a) Device mounted on a glass-epoxy board (a)
- (b) Device mounted on a glass-epoxy board (b)

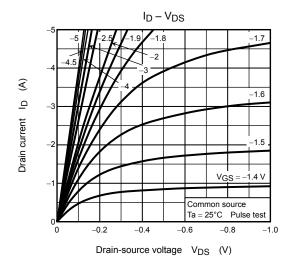


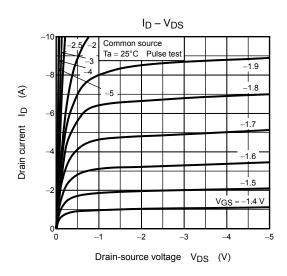


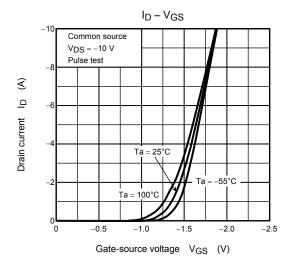
Note 3: $V_{DD} = -10~V$, $T_{ch} = 25^{\circ}C$ (initial), L = 0.5~mH, $R_G = 25~\Omega$, $I_{AR} = -3.0~A$

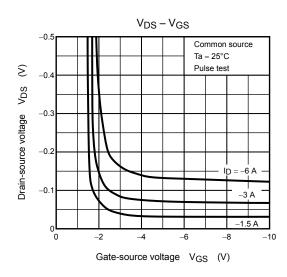
Note 4: Repetitive rating: pulse width limited bymaximum channel temperature

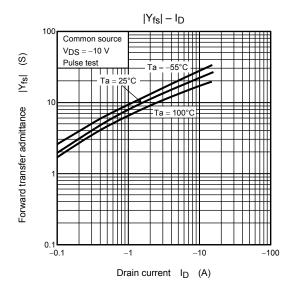
Note 5: A dot on the lower left of the marking indicates Pin 1.

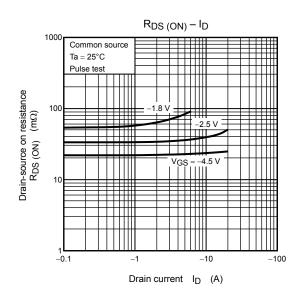


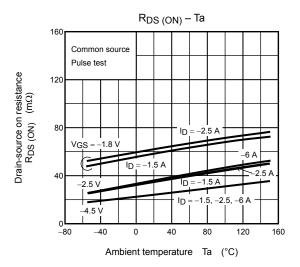


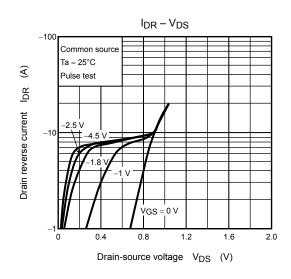


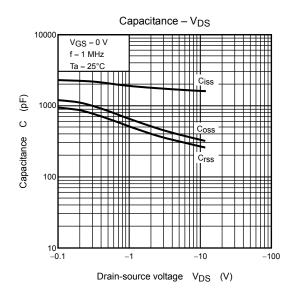


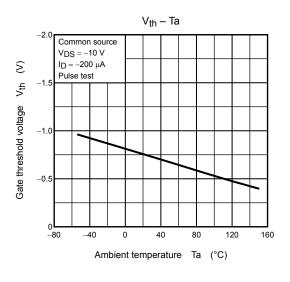


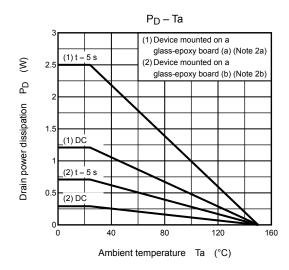


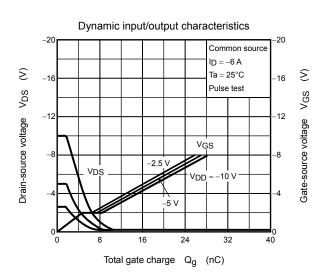


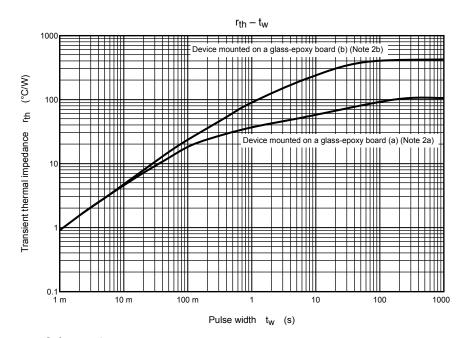


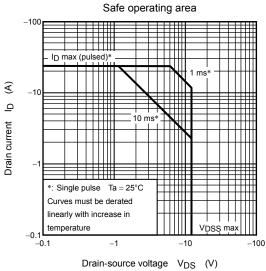












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